

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Michael E. Fossey et al.                      Art Unit : Unknown  
Serial No. : New Continuation Application              Examiner : Unknown  
Filed : June 24, 2003  
Title : WAFER INSPECTION SYSTEM FOR DISTINGUISHING PITS AND  
PARTICLES

Commissioner for Patents  
Washington, D.C. 20231

**INFORMATION DISCLOSURE STATEMENT**

Under 35 USC §120, this application relies on the earlier filing dates of application serial number 10/301,677, filed on November 22, 2002, 09/906,062, filed on July 17, 2001, serial number 09/624,502, filed July 24, 2000, serial number 08/958,230, filed October 27, 1997, and serial number 08/399,962, filed March 6, 1995. The attached list of references were submitted to and/or cited by the Office in the prior applications and, therefore, are not provided in this application.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: June 24, 2003

  
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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 03351-009005	Application No. Continuation Application
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Michael E. Fossey et al.	
		Filing Date June 24, 2003	Group Art Unit

U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	3,749,496	07/1973	Hietanen et al.			
	AB	3,904,293	09/1975	Gee			
	AC	4,297,032	10/1981	Temple			
	AD	4,314,763	02/1982	Steigmeier et al.			
	AE	4,441,124	04/1984	Heebner et al.			
	AF	4,448,527	05/1984	Milana			
	AG	4,469,442	09/1984	Reich			
	AH	4,505,585	03/1985	Yoshikawa et al.			
	AI	4,508,450	04/1985	Ohshima et al.			
	AJ	4,541,712	09/1985	Whitney			
	AK	4,630,276	12/1986	Moran			
	AL	4,740,708	04/1988	Batchelder			
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	AAA	5,032,734	07/1991	Orazio, Jr. et al.			

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
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	ACC	5,108,176	04/1992	Malin et al.			
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	AEE	5,127,726	07/1992	Moran			
	AFF	5,177,559	01/1993	Batchelder et al.			
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	AHH	5,191,466	03/1993	Gross et al.			
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### Foreign Patent Documents or Published Foreign Patent Applications

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							Yes	No
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	ADDD	2 321 964 A	08/1988	Great Britain				
	AEEE	61-240663	10/1986	Japan				
	AFFF	2-216035	08/1990	Japan				
	AGGG	3-128445	05/1991	Japan				
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	AMMM	6-229939	08/1994	Japan				
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	AUUU	2661913	06/1997	Japan				
	AVVV	9-210918	08/1997	Japan				
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	AXXX	10-221268	08/1998	Japan				
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	AZZZ	10-282009	10/1998	Japan				
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	AEED	96/28721	09/1996	WIPO				
	AEED	97/12226	04/1997	WIPO				
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	AHHH	Bawolek, "Light Scattering by Spherical Particles on Semiconductor Surfaces," 1992 Ph.D. Dissertation at Arizona State University, pp. I-281
	AIII	Starr et al., "Comparison of Experimentally Measured Differential Scattering Cross Sections of PSL Spheres on Flat Surfaces and patterned Surfaces," SPIE vol. 2862, (Sep. 1996) pp. 130-138
	AJJJ	Wolfe et al., "A Portable Scatterometer for Optical Shop Use," SPIE vol. 675 (1986) pp. 160-165
	AKKK	Magee et al., "Near-specular Performance of a Portable Scatterometer," SPIE vol. 675 (1986) pp. 249-259
	ALLL	Bickel et al., "The Role of Polarized in the Measurement and Characterization of Scattering," SPIE vol. 679 (1986) pp. 91-98
	AMMM	Iafelice et al., "Polarized Light-Scattering Matrix Elements for Select Perfect and Perturbed Optical Surfaces," Applied Optics 26(12) (1987) pp. 2410-2415
	ANNN	Bickel et al., "Stokes Vectors, Mueller Matrices and Polarized Scattered Light: Experimental Applications to Optical Surfaces and All Other Scatters," SPIE vol. 1530 (1991) pp. 7-14
	AOOO	Bickel et al. "Polarized Light Scattering from Metal Surfaces," J. of Applied Physics 61 (12) (1987) pp. 5392-5398
	APPP	Kylner et al., "Scattering Signatures of Isolated Surfaces Features," SPIE vol. 1995 (1993) pp. 66-72
	AQQQ	TMA Technologies, "TMA QuikScan.RTM.Scatterometer," (1991) Brochure, 4 pages
	ARRR	"Manufacturing: Scatterometers Improve Lasers Mirrors," POTONICS SPECTRA vol. 25, Issue 8 (Aug. 1991) p. 100
	ASSS	Rifkin et al., "Design Review of a Complete Angle Scatter Instruments," SPIE vol. 1036 (1988) pp. 116-124
	ATTT	Stover et al., "Optical Scattering Measurement and Analysis," (1995) Second Edition
	AUUU	Wagner et al., "Requirement of Future Measurement Equipment for Silicon Wafers," SPIE vol. 2862 (Sep. 1996) pp. 152-162
	AVVV	Nebeker, "Modeling of Light Scattering from Structures with Particle Contaminants," SPIE vol. 2862 (Sep. 1996) pp. 139-150
	AWWW	Stover et al. "Measurement and Analysis of Scatter from Silicon Wafers," SPIE vol. 2260 (1994) pp. 182-191
	AXXX	Stover et al., "Some Deviations Associated with Vector Perturbation Diffraction Theory," SPIE vol. 511 (1984) pp. 12-17

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	AYYYY	Sasse, "Angular Scattering Measurement and Calculations of Rough Spherically Shaped Carbon Particles" SPIE vol. 2541 (1995) pp. 131-139
	AZZZZ	Nee, "Reflection, Scattering, and Polarization from a Very Rough Black Surface," SPIE vol. 1995 (1993) pp. 202-212
	AAAAAA	Church et al., "Scattering by Anisotropic Grains in Beryllium Mirrors," SPIE vol. 1331 (1990) pp. 12-17
	ABBBBB	Stover, Editor, "Optical Scattering: Applications, Measurement, and Theory II," vol. 1995 (1993), pp. 1-302
	ACCCCC	Videen et al., "Polarized Light Scattered from Rough Surfaces," Opt. Soc. Am. vol. 9, No. 7 (1992), pp. 1111-1118

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